



Form 1649 (Modified)

**Information Disclosure
Statement By Applicant**

(Use Several Sheets if Necessary)

Attorney Docket No: U.S.
ARTCP031 10/074,517
Applicant: TEMPLETON et al.
Filing Date: February 2, 2002
Group: 2812

U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
SHB	A	6,246,618	06/2001	Yamamoto et al.	365	200	
SHB	B	5,936,977	08/1999	Churchill et al.	371	22.31	
C							
D							
E							
F							
G							
H							
I							
J							
K							

Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
L								
M								
N								
O								
P								

Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
SHB	R	KIM et al., "Built In Self Repair for Embedded High Density SRAM," Proceedings of the International Test Conference 1998. ITC '98. Washington, DC, October 19-20, 1998, International Test Conference, New York, NY: IEEE, U.S. Vol. Conf. 29, October 19, 1998, pages 1112-1119
SHB	S	DREIBELBIS et al., "Processor-Based Built-In Self-Test for Embedded DRAM," IEEE Journal of Solid-State Circuits, IEEE Inc, New York, US, Vol. 33, No. 11, November 1998, pages 1731-1740
	T	
Examiner		Date Considered

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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